Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/006,126	SHIEH ET AL.	
Examiner	Art Unit	
Joseph Lauture	2819	

	SEAR	CHED	
Class	Subclass	Date	Examiner
341	144	3/17/05	J.L
	145	3/17/05	J-L
	136	3/17/05	54
	146	3/17/05	J-C
	135	3/17/05	J·C

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
341	144	3/17/2005	JL		
341	136	3/17/2005	JL		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East Search	3/17/2005	JL	
			